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Application Number	10/765,505
Filing Date	1/26/2004
First Named Inventor	Luu, et al.
Art Unit	2857
Examiner Name	Not Yet Assigned
Attorney Docket Number	SPEED-P001

[illegible][illegible]

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**Complete if Known**

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Sheet 2 of 2

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Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
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